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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/944,925	08/31/2001	Olga Valerievna Koshkina	STL3054	2253	
7	7590 07/12/2005			EXAMINER	
Kirk A. Cesar	Kirk A. Cesari			KAPADIA, VARSHA A	
Seagate Technological Pro-		ART UNIT	PAPER NUMBER		
1280 Disc Driv	perty DeptSHK2LG	2651			
Shakopee, MN 55379-1863			DATE MAILED: 07/12/2005		

Please find below and/or attached an Office communication concerning this application or proceeding.

		App	lication No.	Applicant(s)				
			944,925	KOSHKINA ET AL	<b>-</b> .			
Office Action Summary		Exar	miner	Art Unit				
		Vars	ha A. Kapadia	2651				
 Period for	The MAILING DATE of this commun Reply	ication appears o	on the cover sheet v	vith the correspondence ad	idress			
THE M - Extensi after SI - If the po - If NO p - Failure Any rep	RTENED STATUTORY PERIOD F AILING DATE OF THIS COMMUN ons of time may be available under the provisions X (6) MONTHS from the mailing date of this come period for reply specified above is less than thirty (3 eriod for reply is specified above, the maximum st to reply within the set or extended period for reply by received by the Office later than three months patent term adjustment. See 37 CFR 1.704(b).	ICATION. of 37 CFR 1.136(a). In nunication. i0) days, a reply within t atutory period will apply will, by statute, cause t	n no event, however, may a he statutory minimum of th and will expire SIX (6) MO he application to become A	reply be timely filed irty (30) days will be considered timel NTHS from the mailing date of this c BANDONED (35 U.S.C. § 133).				
Status								
1)⊠ F	Responsive to communication(s) file	ed on 17 Decemb	ber 2004.					
•	•	2b)☐ This action						
3)□ S	Since this application is in condition for allowance except for formal matters, prosecution as to the merits is closed in accordance with the practice under <i>Ex parte Quayle</i> , 1935 C.D. 11, 453 O.G. 213.							
Dispositio	n of Claims							
5)□ C 6)図 C 7)□ C	Claim(s) <u>1,2,4,5,8-13,15,17 and 25-</u> a) Of the above claim(s) is/a Claim(s) is/are allowed. Claim(s) <u>1,2,4,5,8-13,15,17 and 25-</u> Claim(s) is/are objected to. Claim(s) are subject to restrict	re withdrawn from 42 is/are rejected	m consideration.					
Applicatio	n Papers							
9)[] T	he specification is objected to by th	e Examiner.						
10)∐ T	10) ☐ The drawing(s) filed on is/are: a) ☐ accepted or b) ☐ objected to by the Examiner.							
Δ	pplicant may not request that any obje	ction to the drawin	g(s) be held in abeya	ince. See 37 CFR 1.85(a).				
	teplacement drawing sheet(s) including the oath or declaration is objected to		•					
Priority un	der 35 U.S.C. § 119							
a) 1 2 3	cknowledgment is made of a claim  All b) Some * c) None of:  Certified copies of the priority  Copies of the certified copies  application from the Internation  e the attached detailed Office action	documents have documents have of the priority do anal Bureau (PC)	e been received. e been received in a cuments have been F Rule 17.2(a)).	Application No n received in this National	Stage			
Attachment(s	s)							
	of References Cited (PTO-892)			Summary (PTO-413)				
3) 🔲 Informa	of Draftsperson's Patent Drawing Review (F tion Disclosure Statement(s) (PTO-1449 or No(s)/Mail Date			(s)/Mail Date Informal Patent Application (PT0 	D-152)			

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This office action is responsive to the amendment filed on December 17,2004.

## Rejection Under 35 U.S.C. 103

The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:

(a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.

Claims 1-2, 4, 8-13, 15, 17, 25-36 and 38-42 are rejected under 35 U.S.C. 103(a) as being unpatentable over Smith (6,384,995) in view of Abraham et al (5,527,110).

With regards to claim 1, Smith discloses a method for analyzing a data storage apparatus containing a transducer head (see fig.1 elements 107,108) positioned adjacent a data storage media surface (see fig.1 elements 101-102), the method comprising steps of detecting a defective region of the surface by combining plurality of readback signals received during respective pass (see fig.8 elements 804-807).

Smith fails to disclose step of imaging a characteristic size of the defective region as defined in the claimed language.

Abraham et al., however discloses such for the purpose of analyzing the surface of a data storage medium, see for example figs. 4A and 4B, col.5 lines 14-34 and col.6 lines 14-31.

It would have been obvious to one of ordinary skilled in the art at the time this invention was made to modify the disclosure of Smith with the above teachings from

Abraham et al in order to provide a data storage apparatus having capability of imaging a characteristic size of the defective region to analyze and map the locations of the small variations on a surface of the storage medium.

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With regards to claim 2, Smith discloses step of categorizing the defective region by comparing the size of the defective region to a plurality of category profile (see col.3 lines 11-34).

With regards to claims 4 and 10, Smith defines that the category has an identifier indicating the defects in the magnetic recording layer (scratch/corrosion) see col.8 lines 22-25.

With regards to claims 8-9, see Abraham et al on col.5 14-34, wherein display of the three dimensional data includes X and Y coordinate associated with a corresponding Z coordinate relating to a strength of the readback signal. Abraham et al is relied upon for the same reasons discussed above in this office action.

With regards to claims 11 and 12, Smith discloses step of modifying a list of bad sectors and retaining the modified list in the data storage apparatus (see col.10 lines 51 to 59).

With regards to claim 13, Smith further discloses steps f assigning a value to each of the defective region and reworking the data storage apparatus if an aggregation of the assigned values exceeds a predetermined threshold (see abstract and col.10 lines 51-59).

With regards to claim 15, Smith further discloses that the method steps as discussed with respect to claims 1 and 13 are applicable upon a multiplicity of other storage device as claimed (see for example fig. 1, col.5 lines 4-26 and col.10 lines 51-59, wherein Smith also discloses capability of rejecting drive that contains larger defects).

With regards to claim 17, see Smith in fig.1 elements 104, 109 and col.4 lines 22-28.

Claims 25-36 and 38-42 are drawn to the apparatus of using the corresponding method recited in claims 1-2, 4, 8-13, 15, 17, respectively. Therefore apparatus claims 25-36 and 38-42

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correspond to method claims 1-2, 4, 8-13, 15, 17 and are rejected for the same reasons of obviousness as used above.

Claims 31 and 35 further specify the respective dimension of the scratch, i.e. "... a length is greater than a width by a factor of about 2.5". However, defining such dimension is considered as routine engineering capability and no unexpected are results are to occur. Claims 31 and 35 are rejected for the same reasons of obviousness as used above.

Claims 5 and 37 are rejected under 35 U.S.C. 103(a) as being unpatentable over Smith in view of Abraham et al as applied to claims 1-2, 4, 8-13, 15, 17, 25-36 and 38-42 above, and further in view of Bang (6,151,180).

With regards to claims 5 and 37, Smith in view of Abraham et al discloses the invention as discussed above in this office action, but fails to further specify that he defective region is unreliable if a ratio defined by a size of a portion of the defective region with a less than expected readback signal strength...

However, such is disclosed by Bang (see col.3 lines 33-67).

It would have been obvious to one of ordinary skill in the art at the time this invention was made to modify Smith in view of Abraham et al with the above teaching from Bang in order to provide a storage apparatus having a capability of accurately determining which specific portion of the surface is unreliable and hence to increase the reliability of the storage medium.

## Response to Remarks

Applicant's arguments filed on 9/16/04 have been considered but are not persuasive since Abraham does provide a motivation, provided in the office action, for using the imaging

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limitation where a defective region is detected. Since this limitation is not integrally tied to the method of defect detection, and can be applied irrespective of the method of defect detection, combining the teaching of Abraham et al with the teachings of Smith is not problematic.

## Conclusion

THIS ACTION IS MADE FINAL. Applicant is reminded of the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date of this final action and the advisory action is not mailed until after the end of the THREE-MONTH shortened statutory period, then the shortened statutory period will expire on the date the advisory action is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of the advisory action. In no event, however, will the statutory period for reply expire later than SIX MONTHS from the mailing date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Varsha A. Kapadia whose telephone number is (571) 272-7557. The examiner can normally be reached on Mon Tue and Thurs. from 6:30 AM to 2:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, David Hudspeth can be reached on 571 272 7843. The fax phone number for the organization where this application or proceeding is assigned is 703-872-9306.

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Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

VK

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